

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill

Art Unit : 1656

Serial No. : 10/659,103

Examiner : Unknown

Filed : September 9, 2003

Title : MEASUREMENT AND COMPENSATION OF ERRORS IN
INTERFEROMETERS

MAIL STOP AMENDMENT

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

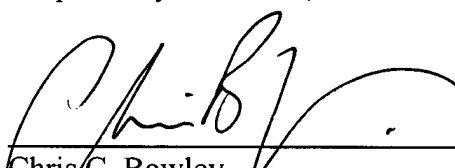
INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 2/2/2005

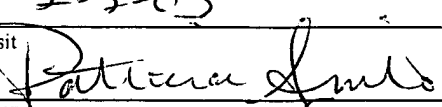

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

2-2-05
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Signature
Patricia Smith
Typed or Printed Name of Person Signing Certificate

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
09712-333001Application No.
10/659,103**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR 1.98(b))

Applicant
Henry A. HillFiling Date
September 9, 2003Group Art Unit
1656**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	US 2003/009067 5	05/15/03	Fujiwara			
	AB	US 2002/008967 1	07/11/02	Hill			
	AC	US 2001/003595 9	11/01/01	Hill			
	AD	6,330,105	12/11/01	Rozelle et al.			
	AE	6,304,318	10/16/01	Matsumoto			
	AF	6,252,668	06/26/01	Hill			
	AG	6,246,481	06/12/01	Hill			
	AH	6,236,507	05/22/01	Hill et al.			
	AI	6,181,420	01/30/01	Badami et al.			
	AJ	6,159,644	12/12/00	Hidetoshi			
	AK	6,134,007	10/17/00	Naraki et al.			
	AL	6,046,792	04/04/00	Van Der Werf et al.			
	AM	6,040,096	03/21/00	Kakizaki			
	AN	6,020,964	02/01/00	Loopstra et al.			
	AO	6,008,902	12/28/99	Rinn			
	AP	5,801,832	09/01/98	Van Der Brink			
	AQ	5,781,277	07/14/98	Iwamoto			
	AR	5,757,489	05/26/98	Kawakami			
	AS	5,757,160	05/26/98	Kreuzer			
	AT	5,764,361	06/09/98	Kato et al.			
	AU	5,724,136	03/03/98	Zanoni			
	AV	5,663,893	09/02/97	Wampler et al.			
	AW	5,663,793	09/02/97	de Groot			
	AX	5,491,550	02/13/96	Dabbs			
	AY	5,408,318	04/18/95	Slater			

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-333001	Application No. 10/659,103
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Henry A. Hill	
		Filing Date September 9, 2003	Group Art Unit 1656

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AZ	5,187,543	02/16/93	Ebert			
	AAA	5,151,749	09/29/92	Tanimoto et al.			
	ABB	5,114,234	05/19/92	Otsuka et al.			
	ACC	5,064,289	11/12/91	Bockman			
	ADD	4,881,816	11/21/89	Zanoni			
	AEE	4,859,066	08/22/89	Sommargren			
	AFF	4,802,765	02/07/89	Young et al.			
	AGG	4,790,651	12/13/88	Brown et al.			
	AHH	4,711,573	12/08/87	Wijntjes et al.			
	AII	4,662,750	05/07/87	Barger			
	AJJ	4,606,638	08/19/86	Sommargren			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AKK	WO 01/90686	11/29/01	WIPO				
	ALL	JP 10-260009 Translation of Abstract Only	09/29/98	Japan			X	
	AMM	JP 7-351078	12/25/95	Japan				
	ANN	JP 8-117083 Abstract Only	04/15/96	Japan			X	
	AOO	JP 9-178415 Translation of Abstract Only	07/11/97	Japan			X	
	APP	JP 9-280822 Translation of Abstract Only	10/31/97	Japan			X	

Other Documents (include Author, Title, Date, and Place of Publication)

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Examiner Initial	Desig. ID	Document
	AQQ	Bennett, S.J. . "A Double-Passed Michelson Interferometer." Optics Communications, 4:6, pp. 428-430, 1972.
	ARR	Wu et al. "Analytical modeling of the periodic nonlinearity in heterodyne interferometry." Applied Optics, 37:28, pp. 6696-6700, 1998.
	ASS	Hines et al. "Sub-Nonometer Laser Metrology – Some Techniques and Models. ESO Conference on High-Resolution Imaging by Interferometry II, pp.1195-1204, 1991
	ATT	Bobroff, Norman. "Recent advances in displacement measuring interferometry." Meas. Sci. Technol. 4, pp. 907-926, 1993.
	AUU	Oka et al. "Polarization heterodyne interferometry using another local oscillator beam." Optics Communications, 92, pp. 1-5, 1992.
	AVV	Badami et al. "Investigation of NonLinearity in High Accuracy Heterodyne Laser Interferometry." American Society for Precision Engineering, 1997 Proceedings, 16, pp. 153-156, 1997.
	AWW	Bobroff, Norman. "Residual errors in laser interferometry from air turbulence and nonlinearity." Applied Optics, 26:13, pp. 2676-2686, 1987.

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